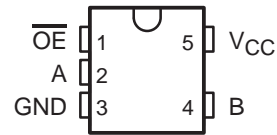


SN74CBTLV1G125 LOW-VOLTAGE SINGLE FET BUS SWITCH

SCDS057D – MARCH 1998 – REVISED MAY 2000

- 5- Ω Switch Connection Between Two Ports
- Isolation Under Power-Off Conditions
- Packaged in Plastic Small-Outline Transistor (DBV, DCK) Packages

DBV OR DCK PACKAGE
(TOP VIEW)



description

The SN74CBTLV1G125 features a single high-speed line switch. The switch is disabled when the output-enable (\overline{OE}) input is high.

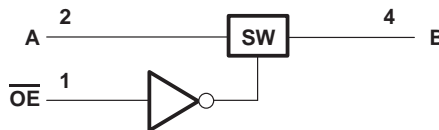
To ensure the high-impedance state during power up or power down, \overline{OE} should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The SN74CBTLV1G125 is characterized for operation from -40°C to 85°C .

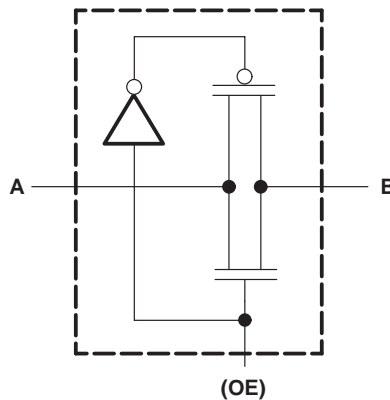
FUNCTION TABLE

INPUT \overline{OE}	FUNCTION
L	A port = B port
H	Disconnect

logic diagram (positive logic)



simplified schematic, each FET switch



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PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.

**TEXAS
INSTRUMENTS**

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SN74CBTLV1G125

LOW-VOLTAGE SINGLE FET BUS SWITCH

SCDS057D – MARCH 1998 – REVISED MAY 2000

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 4.6 V
Input voltage range, V_I (see Note 1)	–0.5 V to 4.6 V
Continuous channel current	128 mA
Input clamp current, I_{IK} ($V_{I/O} < 0$)	–50 mA
Package thermal impedance, θ_{JA} (see Note 2): DBV package	206°C/W
DCK package	252°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.
2. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 3)

		MIN	MAX	UNIT
V_{CC}	Supply voltage	2.3	3.6	V
V_{IH}	High-level control input voltage	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$ 1.7		V
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$ 2		
V_{IL}	Low-level control input voltage	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$ 0.7		V
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$ 0.8		
T_A	Operating free-air temperature	–40	85	°C

NOTE 3: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		MIN	TYP [‡]	MAX	UNIT
V_{IK}	$V_{CC} = 3 \text{ V}$,	$I_I = -18 \text{ mA}$			–1.2	V
I_I	$V_{CC} = 3.6 \text{ V}$,	$V_I = V_{CC}$ or GND			±1	μA
I_{off}	$V_{CC} = 0$,	V_I or $V_O = 0$ to 3.6 V			10	μA
I_{CC}	$V_{CC} = 3.6 \text{ V}$,	$I_O = 0$, $V_I = V_{CC}$ or GND			10	μA
ΔI_{CC} [§]	Control inputs	$V_{CC} = 3.6 \text{ V}$, One input at 3 V, Other inputs at V_{CC} or GND			300	μA
C_i	Control inputs	$V_I = 3 \text{ V}$ or 0		2.5		pF
$C_{io(OFF)}$	$V_O = 3 \text{ V}$ or 0,	$\overline{OE} = V_{CC}$		7		pF
r_{on} [¶]	$V_{CC} = 2.3 \text{ V}$, TYP at $V_{CC} = 2.5 \text{ V}$	$V_I = 0$	$I_I = 64 \text{ mA}$	7	10	Ω
			$I_I = 24 \text{ mA}$	7	10	
		$V_I = 1.7 \text{ V}$,	$I_I = 15 \text{ mA}$	15	25	
	$V_{CC} = 3 \text{ V}$	$V_I = 0$	$I_I = 64 \text{ mA}$	5	7	
			$I_I = 24 \text{ mA}$	5	7	
		$V_I = 2.4 \text{ V}$,	$I_I = 15 \text{ mA}$	10	15	

[‡] All typical values are at $V_{CC} = 3.3 \text{ V}$ (unless otherwise noted), $T_A = 25^\circ\text{C}$.

[§] This is the increase in supply current for each input that is at the specified voltage level rather than V_{CC} or GND.

[¶] Measured by the voltage drop between the A and B terminals at the indicated current through the switch. On-state resistance is determined by the lower of the voltages of the two (A or B) terminals.



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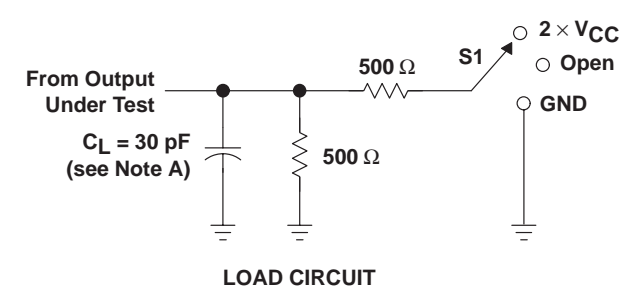
switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 and 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	$V_{CC} = 2.5\text{ V} \pm 0.2\text{ V}$		$V_{CC} = 3.3\text{ V} \pm 0.3\text{ V}$		UNIT
			MIN	MAX	MIN	MAX	
t_{pd}^\dagger	A or B	B or A	0.35		0.25		ns
t_{en}	\overline{OE}	A or B	1	4	1	4	ns
t_{dis}	\overline{OE}	A or B	1	5	1	4.1	ns

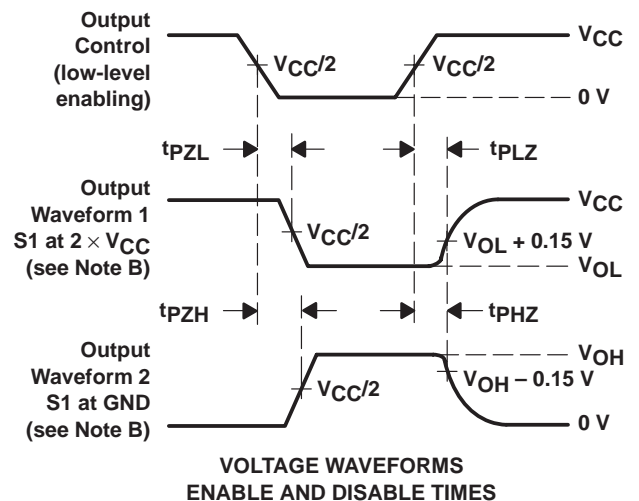
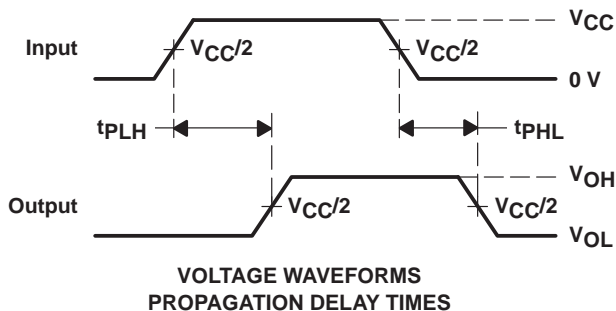
[†] The propagation delay is the calculated RC time constant of the typical on-state resistance of the switch and a load capacitance of 50 pF, when driven by an ideal voltage source (zero output impedance).

PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.5\text{ V} \pm 0.2\text{ V}$



TEST	S1
t_{pd}	Open
t_{PLZ}/t_{PZL}	2 $\times V_{CC}$
t_{PHZ}/t_{PHL}	GND



- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: PRR $\leq 10\text{ MHz}$, $Z_O = 50\text{ }\Omega$, $t_r \leq 2\text{ ns}$, $t_f \leq 2\text{ ns}$.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en} .
 - G. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

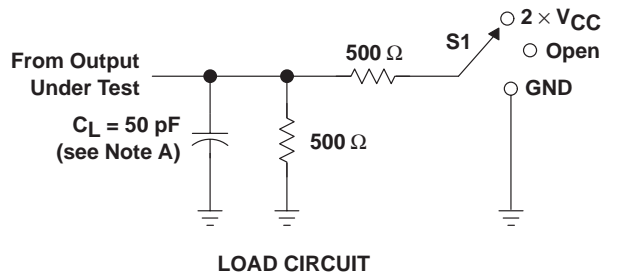
SN74CBTLV1G125

LOW-VOLTAGE SINGLE FET BUS SWITCH

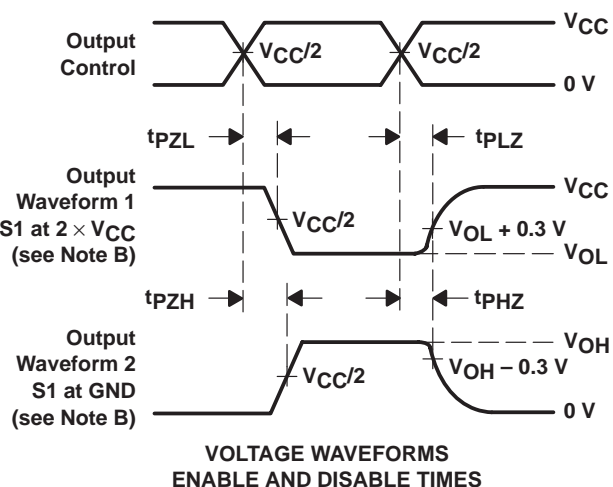
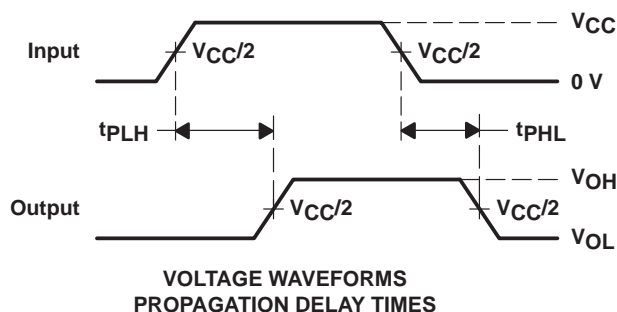
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PARAMETER MEASUREMENT INFORMATION

$$V_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V}$$



TEST	S1
t_{pd} t_{PLZ}/t_{PZL} t_{PHZ}/t_{PZH}	Open 2 $\times V_{CC}$ GND



- NOTES:
- C_L includes probe and jig capacitance.
 - Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2 \text{ ns}$, $t_f \leq 2 \text{ ns}$.
 - The outputs are measured one at a time with one transition per measurement.
 - t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - t_{PZL} and t_{PZH} are the same as t_{en} .
 - t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 2. Load Circuit and Voltage Waveforms

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